Search Notes Application/Control No. Applicant(s)/Patent Under Reexamination CHOWN, DAVID Examiner Liu, Li Art Unit 2613

SEARCHED				
Class	Subclass	Date	Examiner	
372	102	08/03/2006	LL	
398	41-43, 152, 129, 58, 122, 125	08/03/2006, 02/08/2007	LL	
385	12, 24, 93, 49	08/03/2006, 02/08/2007	LL	
250	25	08/03/2006	LL	

SEARCH NOTES			
Search Notes	Date	Examiner	
EAST			
USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB	08/03/2006, 02/08/2007, 11/27/2007, 5/31-6/13, 2008; 12/29-12/30, 2008	LL	
Google	08/03/2006	LL	
IEEE	08/03/2006, 12/30/2008	LL	

INTERFERENCE SEARCH			
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